

April 2000 PRELIMINARY

FDW2504P

Dual P-Channel 2.5V Specified PowerTrench MOSFET

General Description

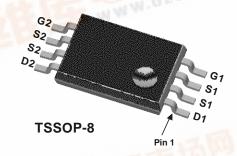
This P-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V – 12V).

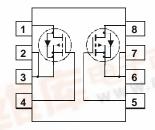
Applications

- · Load switch
- Motor drive
- DC/DC conversion
- · Power management

Features

- -3.8 A, -20 V, $R_{DS(ON)} = 0.043 \ \Omega$ @ $V_{GS} = -4.5 \ V$ $R_{DS(ON)} = 0.070 \ \Omega$ @ $V_{GS} = -2.5 V$
- Extended V_{GSS} range (±12V) for battery applications
- Low gate charge
- High performance trench technology for extremely low R_{DS(ON)}
- Low profile TSSOP-8 package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	-3.8	A
	- Pulsed		-30	-C.C.C
P _D	Power Dissipation	(Note 1a)	1.0	W
		(Note 1b)	0.6	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

R _{eJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	125	°C/W
7.6	M M M.	(Note 1b)	208	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity	
2504P	FDW2504P	13"	12mm	3000 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			I	I	I
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$, Referenced to $25^{\circ} C$		-16		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = -12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			-100	nA
I_{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.6	-1	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$, Referenced to $25^{\circ} C$		3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$\begin{array}{cccccccccccccccccccccccccccccccccccc$		0.036 0.056 0.049	0.043 0.070 0.069	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, \qquad V_{DS} = -5 \text{ V}$	-15			Α
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -3.5 \text{ A}$		13.2		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		1015		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		446		pF
C _{rss}	Reverse Transfer Capacitance			118		pF
Switchir	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -5 \text{ V}, \qquad I_{D} = -1 \text{ A},$		11	20	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		18	32	ns
t _{d(off)}	Turn-Off Delay Time			34	55	ns
t _f	Turn-Off Fall Time	7		34	55	ns
Q _g	Total Gate Charge	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -3.8 \text{ A},$		9.7	16	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -4.5 \text{ V}$		2.2		nC
Q_{gd}	Gate-Drain Charge			2.4		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				-0.83	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -0.83 \text{ A (Note 2)}$		-0.7	-1.2	V

Notes

^{1.} R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.

a) $\rm\,R_{\rm \theta JA}$ is 125°C/W (steady state) when mounted on a 1 inch² copper pad on FR-4.

b) R_{BJA} is 208°C/W (steady state) when mounted on a minimum copper pad on FR-4.

^{2.} Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%

Typical Characteristics

R_{DS(ON)}, NORMALIZED DRAIN-SOURCE ON-RESISTANCE

0.6

Vgs = -4.5V

-25

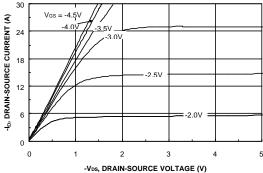


Figure 1. On-Region Characteristics.

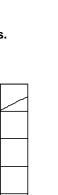


Figure 3. On-Resistance Variation withTemperature.

T_J, JUNCTION TEMPERATURE (°C)

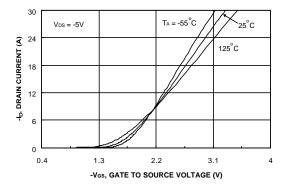


Figure 5. Transfer Characteristics.

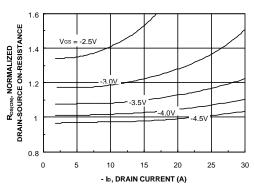


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

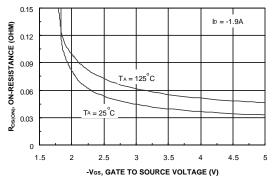


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

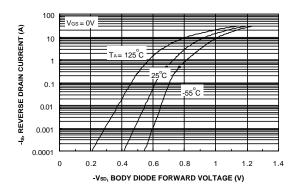
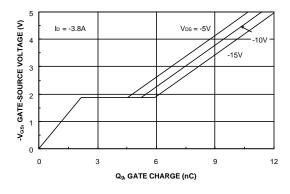


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



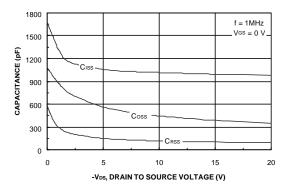


Figure 7. Gate Charge Characteristics.

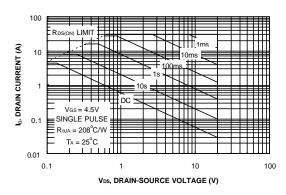


Figure 8. Capacitance Characteristics.

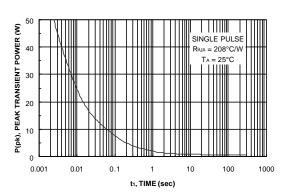


Figure 9. Maximum Safe Operating Area.



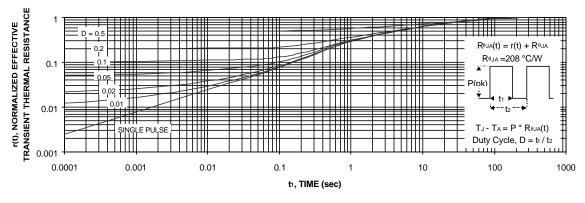


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

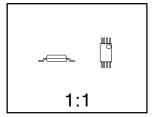
TSSOP-8 Package Dimensions



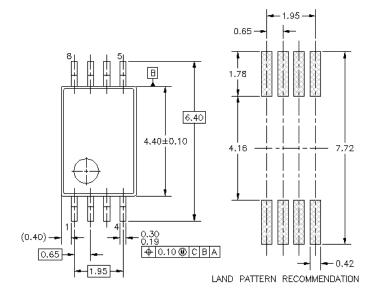
TSSOP-8 (FS PKG Code S4)

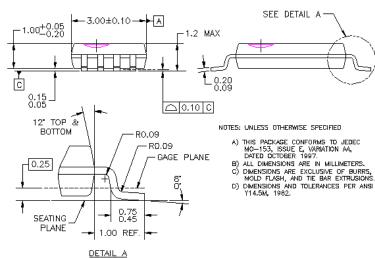


MTCOBREVE



Scale 1:1 on letter size paper
Dimensions shown below are in millimeters
Part Weight per unit (gram): 0.0334





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